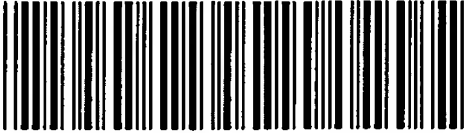


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/010,525	CHAU ET AL.	
	Examiner	Art Unit	
	Steven Loke	2811	

SEARCHED			
Class	Subclass	Date	Examiner
257	368, 382, 383, 384, 387, 388	11/12/2002	QV
257	412, 413	11/12/2002	QV
257	616	11/12/2002	QV
438	199, 217	11/13/2002	QV
438	300, 585	11/13/2002	QV
438	587, 588	11/13/2002	QV
438	589, 592	11/13/2002	QV
438	595, 752	11/13/2002	QV
438	933	11/13/2002	QV
above	updated	4/11/2003	QV
above	updated	9/4/2003	QV
above	updated	1/8/2006	sl

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Appl. 08/884,912 refs. checked	1/8/2006	SL
Appl. 09/115,405 refs. checked	1/8/2006	SL
Appl. 09/654,315 refs. checked	1/8/2006	SL
Appl. 08/363,749 checked	1/8/2006	sl